

WHAT IS CLAIMED IS

1. An inspection apparatus for inspecting a plurality of semiconductor integrated circuits mounted on a base board, the apparatus comprising:
 - 5 a plurality of relay pins electrically connected to a wiring pattern laid on the base board;
 sockets provided on the base board, each housing a semiconductor integrated circuit;
 exchange boards, each electrically connecting socket terminals of a socket to a specific relay pin; and
 spacers interposed between each of the exchange boards and the base board.
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 - 15 2. The inspection apparatus according to claim 1, wherein the exchange board is a film-like sheet board, and a reinforcement plate for reinforcing the sheet-like board is provided between the sheet-like board and the spacers.
 - 20 3. The inspection apparatus according to claim 1, wherein the exchange board is provided with a pin socket for holding the relay pins, and the relay pins are removably attached to the exchange board.
 - 25 4. The inspection apparatus according to claim 1, wherein the base board has a pin socket for holding the relay pins, and the exchange board is removable from the base board together with the relay pins.
 - 30 5. The inspection apparatus according to claim 1, wherein a circuit element or a pattern for receiving a circuit element is formed in an area on the base board, the area opposing the exchange board.

6. The inspection apparatus according to claim 1, wherein
a circuit element or a pattern for receiving a circuit element
is formed in an area on the exchange board, the area opposing
the base board.

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7. An inspection apparatus for inspecting a plurality of
semiconductor integrated circuits mounted on a base board, wherein
the base board comprises:

- aplurality of connection terminals electrically connected
10 to terminals of an inspection main unit;
- a plurality of wiring patterns connected to terminals of
a semiconductor integrated circuit; and
- a junction unit for changing the state of a junction formed
between the connection terminals and the wiring pattern.

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8. The inspection apparatus according to claim 7, wherein
the junction unit includes a pin socket for connecting the wiring
pattern to the connection terminals when a pin is inserted into
20 the pin socket, and the pin socket is interposed between each
of a plurality of wiring patterns and a single connection terminal
and/or between each of a plurality of connection terminals and
a single wiring pattern.

9. The inspection apparatus according to claim 7, wherein
25 the junction unit includes an element mount pattern for connecting
the wiring pattern to the connection terminals when a
short-circuit element is mounted on the element mount pattern,
and the element mount pattern is provided between each of a
plurality of wiring patterns and a single connection terminal
30 and/or between each of a plurality of connection terminals and
a single wiring pattern.

10. The inspection apparatus according to claim 7, wherein
the junction unit includes at least one of a dip switch for switching
a junction between each of a plurality of wiring patterns and
a single connection terminal, and a dip switch for switching a
5 junction between a plurality of connection terminals and a single
wiring pattern.

11. An inspection method for inspecting a semiconductor
integrated circuit using the inspection apparatus according to
10 claim 1.